

**IN THE SPECIFICATION:**

Please insert the following paragraph at the beginning of the specification.

This application is a 371 of international application PCT/JP2005/002398, which claims priority based on Japanese patent application Nos. 2004-039461 and 2004-040930 filed February 17 and February 18, 2004, respectively, which are incorporated herein by reference.

Please replace the paragraph beginning on page 23, line 19, with the following rewritten paragraph:

K. Estimation of microplanarity due to heat treatment:

The heat treatment was carried out by leaving a film for 24 hours in an oven controlled at 100 °C. The microplanarities of layer (A) before and after the heat treatment were determined at a measurement area magnification of 41.6 times and an area for measurement of 239 x 239 $\mu$ m (0.057 mm<sup>2</sup>) using a non-contact type three dimensional roughness meter TOPO-3D manufactured by WYKO Corporation. By an analyzing soft (ver. 4.90) incorporated into the roughness meter, the relative powers at spatial frequencies of ~~10 cm<sup>-1</sup> and 200 cm<sup>-1</sup>~~ 10 mm<sup>-1</sup> and 200 mm<sup>-1</sup> were determined. The

measurement was carried out ten times, and the average value was defined as the relative power. As to WRa, only the film before the heat treatment was measured.